

5 CLAIMS:

1. A probe station for probing a device under test comprising:
 - (a) a support for holding said device under test;
 - (b) a probing device for testing said device under test while being
10 supported by said support;
 - (c) a cable connecting said probing device to a test instrument, said
cable including:
 - (i) a first conductor, a first dielectric, and a second conductor,
15 where said first dielectric is between said first conductor
and said second conductor;
 - (ii) a second dielectric, and a third conductor, where said
second dielectric is between said second conductor and said
third conductor;
 - (iii) further including a first layer of material between said
20 second dielectric and said third conductor of suitable
composition for reducing triboelectric current generation
between said second dielectric and said third conductor to
less than that which would occur were said second
dielectric and said third conductor to directly adjoin each
25 other.

5 2. The probe station of claim 1 further comprising a second layer of material
between said first dielectric and said second conductor of suitable composition for
reducing triboelectric current generation between said first dielectric and said second
conductor to less than that which would occur were said first dielectric and said second
conductor to directly adjoin each other.

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3. A probe station for probing a device under test comprising:

- (a) a support for holding said device under test;
- (b) a probing device for testing said device under test while being
supported by said support;

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- (c) a cable connecting said probing device to a test instrument, said
cable including:

- (i) a first conductor, a first dielectric, and a second conductor,
where said first dielectric is between said first conductor
and said second conductor;

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- (ii) a second dielectric, and a third conductor, where said
second dielectric is between said second conductor and said
third conductor;

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- (iii) further including a first layer of material between said
second dielectric and said second conductor of suitable
composition for reducing triboelectric current generation
between said second dielectric and said second conductor to

5 less than that which would occur were said second
dielectric and said second conductor to directly adjoin each
other.

4. The probe station of claim 3 further comprising a second layer of material
10 between said first dielectric and said second conductor of suitable composition for
reducing triboelectric current generation between said first dielectric and said second
conductor to less than that which would occur were said first dielectric and said second
conductor to directly adjoin each other.

15 5. A probe station for probing a device under test comprising:
(a) a support for holding said device under test;
(b) a probing device for testing said device under test while being
supported by said support;
(c) a cable connecting said probing device to a test instrument, said
20 cable including:
(i) a first conductor, a first dielectric, and a second conductor,
where said first dielectric is between said first conductor
and said second conductor;
(ii) a second dielectric, and a third conductor, where said
25 second dielectric is between said second conductor and said
third conductor;

5 (iii) further including a first layer of material between said first
dielectric and said first conductor of suitable composition
for reducing triboelectric current generation between said
first dielectric and said first conductor to less than that
which would occur were said first dielectric and said first
10 conductor to directly adjoin each other.

6. The probe station of claim 5 further comprising a second layer of material
between said first dielectric and said second conductor of suitable composition for
reducing triboelectric current generation between said first dielectric and said second
15 conductor to less than that which would occur were said first dielectric and said second
conductor to directly adjoin each other.

7. A cable comprising

(a) a first conductor, a first dielectric, and a second conductor, where
20 said first dielectric is between said first conductor and said second
conductor;

(b) a second dielectric, and a third conductor, where said second
dielectric is between said second conductor and said third
conductor;

25 (c) further including a first layer of material between said second
dielectric and said third conductor of suitable composition for

5 reducing triboelectric current generation between said second
dielectric and said third conductor to less than that which would
occur were said second dielectric and said third conductor to
directly adjoin each other.

10 8. The cable of claim 7 further comprising a second layer of material between
said first dielectric and said second conductor of suitable composition for reducing
triboelectric current generation between said first dielectric and said second conductor to
less than that which would occur were said first dielectric and said second conductor to
directly adjoin each other.

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9. A cable comprising:

(a) a first conductor, a first dielectric, and a second conductor, where
said first dielectric is between said first conductor and said second
conductor;

20 (b) a second dielectric, and a third conductor, where said second
dielectric is between said second conductor and said third
conductor;

(c) further including a first layer of material between said second
dielectric and said second conductor of suitable composition for
25 reducing triboelectric current generation between said second
dielectric and said second conductor to less than that which would

5 occur were said second dielectric and said second conductor to
directly adjoin each other.

10. The cable of claim 9 further comprising a second layer of material between
said first dielectric and said second conductor of suitable composition for reducing
10 triboelectric current generation between said first dielectric and said second conductor to
less than that which would occur were said first dielectric and said second conductor to
directly adjoin each other.

11. A cable comprising:

- 15 (a) a first conductor, a first dielectric, and a second conductor, where
said first dielectric is between said first conductor and said second
conductor;
- (b) a second dielectric, and a third conductor, where said second
dielectric is between said second conductor and said third
20 conductor;
- (c) further including a first layer of material between said first
dielectric and said first conductor of suitable composition for
reducing triboelectric current generation between said first
dielectric and said first conductor to less than that which would
25 occur were said first dielectric and said first conductor to directly
adjoin each other.

5 12. The probe station of claim 11 further comprising a second layer of
material between said first dielectric and said second conductor of suitable composition
for reducing triboelectric current generation between said first dielectric and said second
conductor to less than that which would occur were said first dielectric and said second
conductor to directly adjoin each other.

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